Notice of References Cited Application/Control No. 10/694,785 Applicant(s)/Patent Under Reexamination KIDERA, MAKOTO Examiner Helen Rossoshek Applicant(s)/Patent Under Reexamination KIDERA, MAKOTO Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0165704	11-2002	Yang et al.	703/22
*	В	US-2004/0088068	05-2004	Kadosh	700/108
*	С	US-6,304,834	10-2001	Enda	703/4
*	D	US-6,622,059	09-2003	Toprac et al.	700/121
*	Ε	US-5,886,906	03-1999	Tatsumi et al.	703/14
*	F	US-6,577,992	06-2003	Tcherniaev et al.	703/14
*	G	US-5,063,540	11-1991	Takahashi	365/175
*	н	US-6,404,230	06-2002	Cairns et al.	326/68
*	ı	US-6,321,183	11-2001	Tatsumi	703/14
*	J	US-5,687,355	11-1997	Joardar et al.	716/20
*	к	US-6,698,000	02-2004	Tanaka	716/2
*	L	US-6,611,948	08-2003	Tyler et al.	716/6
*	М	US-6,609,233	08-2003	Foltin et al.	716/6

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004198111 A	07-2004	Japan	KOSUGI et al.	G01R 31/26
	0	JP 2001185594 A	07-2001	Japan	TOGO, MITSUHIRO	H01L 21/66
	Р					
	Q					
	R					
	s					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Rogers et al., "Model for the channel-implanted enhancement-mode IGFET", Jul 1986, Electron Devices, IEEE Transactions on, Volume 33, Issue 7, Page(s):955 - 964
	٧	Rosario et al., "MESFET drain mixers: analysis and design", 11-13 April 1989Electrotechnical Conference, Proceedings. 'Integrating Research, Industry and Education in Energy and Communication Engineering', Page(s):343 - 346
	w	Sambandan et al., "Markov model for threshold-voltage shift in amorphous silicon TFTs for variable gate bias", June 2005, Electron Device Letters, IEEE, Volume 26, Issue 6, Page(s):375 - 377 🗆 🗆
	x	

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Application/Control No. Notice of References Cited Application/Control No. 10/694,785 Examiner Helen Rossoshek Applicant(s)/Patent Under Reexamination KIDERA, MAKOTO Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	А	US-6,586,972	07-2003	Wang et al.	327/87
*	В	US-6,581,197	06-2003	Foutz et al.	716/6
*	С	US-6,553,545	04-2003	Stinson et al.	716/4
*	D	US-6,404,230	06-2002	Cairns et al.	326/68
*	Ε	US-6,365,936	04-2002	Shimabukuro et al.	257/350
*	F	US-6,353,235	03-2002	Watanabe	257/48
*	G	US-6,190,933	02-2001	Shimabukuro et al.	438/30
*	н	US-6,185,723	02-2001	Burks et al.	716/6
*	ı	US-6,172,513	01-2001	Contrata	324/756
*	J	US-6,111,424	08-2000	Bosacchi	324/770
*	к	US-5,822,241	10-1998	Chatterjee et al.	365/149
*	L	US-5,761,481	06-1998	Kadoch et al.	703/2
*	М	US-2004/0212016	10-2004	Yasui et al.	257/365

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	ď					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.